

**EMPAD Detector**

The high speed, sensitivity and dynamic range will enable multichannel atomic-scale imaging and analysis of material properties such as electric and magnetic fields not previously possible. The electron microscope pixel array detector (EMPAD) simultaneously captures the spatially and angularly-resolved distribution of all transmitted electrons, allowing acquisition of scattering information to generate images and analytical results in scanning transmission electron microscope (STEM) applications.

**Statement of Prof. David Muller, School of Applied and Engineering Physics, Cornell University**

"The EMPAD records an image frame in less than a millisecond and can detect from 1 to 1,000,000 primary electrons per pixel, per image frame"

If you require more information, please contact us here

Contact

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